

beam (6) and the reflected light (15) can be electronically evaluated and that the frequency shift ($v-v'$) of the reflected light (15) can be determined therefrom.

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coll.

6. (amended) A device as claimed in claim 1, characterized in that the speed of rotation (v) of a rotating defect (14) can be calculated from the frequency shift ($v-v'$) by way of the Doppler formula.

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8. (amended) A device as claimed in claim 1, characterized in that the moving surface (8) is associated with a device for detecting its instantaneous orientation.

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10. (amended) A device as claimed in claim 4, characterized in that the position of a defect (14) on the inspected surface relative to said scale can be determined from the signal detected by the detector (16; 17).

11. (amended) A device as claimed in claim 1, characterized in that the surface (8) to be inspected can move in a rotational as well as in a translational mode.

12. (amended) A device as claimed in claim 1, characterized in that the light beam (2) that is emitted by the light source (1) is